

Title (en)

POSITION CORRECTION SAMPLE, MASS SPECTROMETRY DEVICE, AND MASS SPECTROMETRY METHOD

Title (de)

POSITIONSKORREKTURPROBE, MASSENSPEKTROMETRIEVORRICHTUNG UND MASSENSPEKTROMETRIEVERFAHREN

Title (fr)

ÉCHANTILLON DE CORRECTION DE POSITION, DISPOSITIF DE SPECTROMÉTRIE DE MASSE ET PROCÉDÉ DE SPECTROMÉTRIE DE MASSE

Publication

**EP 3139400 B1 20180228 (EN)**

Application

**EP 16185874 A 20160826**

Priority

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Abstract (en)

[origin: EP3139400A1] According to an embodiment, a position correction sample (20) is used to correct an irradiation position of an ion beam with respect to a sample platform where an analysis object is disposed in mass spectrometry. The position correction sample (20) comprises a stacked body (LB1). The stacked body includes a first layer (201), a second layer (202), and a third layer (203). The first layer includes a first material. The second layer is provided on the first layer. The second layer includes a second material. The third layer is provided on the second layer. The third layer includes a third material.

IPC 8 full level

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